Search Notes				

Application No.	Applicant(s)	
10/658,163	HOESE ET AL.	
Examiner	Art Unit	
Christopher B Shin	2182	

					
SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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SAST (USPAT, epo, JPO, derwat, IBM TOB)	1-16-01	`S
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